

Docket No.:

FORM PTO-1595 (Modified)

(Rev. 03-01)

OMB No. 0651-0027 (exp. 5/31/2002)

POBA/REV03

RECORDATION FORM COVER SHEET

U.S. DEPARTMENT OF COMMERCE

Patent and Trademark Office

PATENTS ONLY

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To the Director of the United States Patent and Trademark Office: Please record the attached original documents or copy thereof.

1. Name of conveying party(ies):

NPTest, LLC

Additional names(s) of conveying party(ies)

☐ Yes ☒ No

3. Nature of conveyance:

☒ Assignment☐ Merger☐ Security Agreement☐ Change of Name☐ OtherExecution Date: July 13, 2004

2. Name and address of receiving party(es):

Name: Credence Systems CorporationAddress: 1421 California CircleCity: Milpitas State/Prov.: CACountry: U.S.A. ZIP: 95035

Additional name(s) & address(es)

☐ Yes ☒ No

4. Application number(s) or patent numbers(s):

If this document is being filed together with a new application, the execution date of the application is:

Patent Application No.

Filing date

B. Patent No.(s)

See Attachment A

See Attachment A

Additional numbers

☒ Yes ☐ No

5. Name and address of party to whom correspondence concerning document should be mailed:

Name: Gregory P. Durbin, Esq.Registration No. 42,503Address: DORSEY & WHITNEY LLP370 Seventeenth Street, Suite 4700City: Denver State/Prov.: COCountry: U.S.A. ZIP: 80202-5647

6. Total number of applications and patents involved:

112

7. Total fee (37 CFR 3.41):.....\$ 4,480.00☐ Enclosed - Any excess or insufficiency should be credited or debited to deposit account☒ Authorized to be charged to deposit account

8. Deposit account number:

04-1415

(Attach duplicate copy of this page if paying by deposit account)

DO NOT USE THIS SPACE

9. Statement and signature.

*To the best of my knowledge and belief, the foregoing information is true and correct and any attached copy is a true copy of the original document.*Gregory P. Durbin

Name of Person Signing



Signature

Oct 12, 2004

Date

36

Total number of pages including cover sheet, attachments, and

Mail documents to be recorded with required cover sheet information to:
Mail Stop Assignment Recordation Services
Director of the United States Patent and Trademark Office
P.O. Box 1450 Alexandria, VA 22313-1450

PATENT

700122479

REEL: 015242 FRAME: 0574

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ATTACHMENT A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CRENDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	03/07/1983	472,427	06/10/1986	4,594,544	Participate Register for Parallel Loading Pin-Oriented Registers In Test Equipment	Inactive	P0081
United States	05/17/1984	611,266	03/17/1987	4,651,038	Gate Having Temperatures-Stabilized Delay	Granted	P0117
United States	05/17/1984	611,454	11/18/1986	4,623,802	Multiple-Stage Gate Network Having Independent Reference Voltage Sources	Inactive	P0118
United States	07/18/1984	631,958	06/16/1987	4,673,917	Method and Apparatus for Minimizing Digital-To-Analog Converter Correction Trims	Granted	P0120
United States	08/16/1985	766,905	09/05/1989	4,864,228	Electron Beam Test Probe for Integrated Circuit Testing	Granted	P0150
United States	11/15/1985	798,592	11/10/1987	4,706,019	Electron Beam Test Probe System for Analyzing Integrated Circuits	Granted	P0132
United States	02/10/1986	828,157	01/26/1988	4,721,909	Apparatus for Pulsing Electron Beams	Granted	P0133
United States	11/19/1986	932,762	01/03/1989	4,795,984	Multi-Marker, Multi-Destination Timing Signal Generator	Granted	P0125
United States	05/17/1988	196,776	03/27/1990	4,912,405	Magnetic Lens and Electron Beam Deflection System	Granted	P0135
United States	11/13/1988	276,359	10/01/1991	5,054,097	Methods and Apparatus for Alignment of Images	Granted	P0165
United States	12/12/1988	284,775	03/20/1990	4,910,698	Sine Wave Generator Using A Cordic Algorithm	Granted	P0128
United States	07/13/1990	553,202	02/25/1992	5,091,693	Dual-Sided Test Head Having Floating Contact Surfaces	Granted	P0180
United States	09/05/1990	577,986	05/18/1993	5,212,443	Event Sequencer for Automatic Test Equipment	Granted	P0148
United States	09/05/1990	577,987	07/06/1993	5,225,772	Automatic Test Equipment System Using Pin Slice Architecture	Granted	P0168
United States	01/14/1991	640,636	08/18/1992	5,140,164	IC Modification with Focused ION Beam	Inactive	P0189
United States	02/13/1991	07/655,255	06/30/1992	5,127,064	High Resolution Image Compression Methods and Apparatus	Granted	P0164
United States	06/04/1991	07/710,768	05/11/1993	5,210,487	Double-Gated Integrating Scheme for Electron Beam Tester	Granted	P0191
United States	07/12/1991	729,510	08/10/1993	5,235,273	Apparatus for Setting Pin Driver/Sensor Reference Voltage Level	Granted	P0194
United States	07/17/1991	732,351	06/16/1992	5,122,989	Data Stream Smoothing Using a FIFO Memory	Granted	P0172
United States	07/25/1991	737,553	09/01/1992	5,144,225	Methods and Apparatus for Acquiring Data from Intermittently Failing Circuits	Granted	P0173
United States	12/30/1991	816,639	02/21/1995	5,392,222	Locating a Field of View in which Selected IC Conductors are Unobscured	Granted	P0184
United States	04/30/1992	876,566	12/12/1995	5,475,624	Test Generation by Environment Emulation	Granted	P0192

PATENT

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Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	08/12/1992	07/928,919	12/14/1993	5,270,643	Pulsed Laser Photoemission Electron-Beam Probe	Granted	P0188
United States	11/23/1992	07/980,371	10/18/1994	5,357,116	Focused ION Beam Processing with Charge Control	Granted	P0204
United States	03/15/1993	031,547	02/18/1997	5,604,819	Determining Offset between Images of an IC	Granted	P0202
United States	03/24/1993	037,507	02/15/1994	5,287,022	Method and Circuit for Controlling Voltage Reflections on Transmissions Lines	Granted	P0193
United States	05/13/1993	62,362	12/19/1995	5,477,139	Event Sequencer for Automatic Test Equipment	Granted	P0148
United States	08/03/1993	100,975	07/04/1995	5,430,400	Driver Circuits for IC Tester	Granted	P0209
United States	09/02/1993	08/115,997	03/28/1995	5,401,972	Layout Overlay for FIB Operations	Granted	P0210
United States	10/12/1993	08/134,330	01/02/1996	5,481,550	Apparatus For Maintaining Stimulation To A Device Under Test After A Test Stops	Granted	P0203
United States	04/15/1994	228,027	06/25/1996	5,530,372	Method of Probing a Net of an IC at an Optimal Probe-Point	Granted	P0211
United States	06/28/1994	08/267,870	10/24/1995	5,461,310	Automatic Test Equipment System Using Pin Slice Architecture	Granted	P0168
United States	06/30/1994	268,790	04/01/1997	5,616,921	Self-Masking FIB Milling	Granted	P0207
United States	05/04/1995	08/434,548	12/23/1997	5,700,526	Insulator Deposition Using Focused Ion Beam	Granted	P0234
United States	06/08/1995	08/488,650	06/10/1997	5,638,005	Predictive Waveform Acquisition	Granted	P0216
United States	07/17/1995	08/503,023	03/24/1998	5,731,984	Vector-Based Waveform Acquisition and Display	Granted	P0239
United States	08/01/1995	08/510,397	07/08/1997	5,646,521	Analog Channel for Mixed Signal VLSI Tester	Granted	P0222
United States	08/01/1995	08/510,395	08/05/1997	5,654,657	Accurate Alignment of Clocks in Mixed-Signal Tester	Granted	P0228
United States	12/15/1995	08/573,071	06/15/1999	5,913,022	Loading Hardware Pattern Memory in Automatic Test Equipment for Testing Circuits	Granted	P0231
United States	04/02/1996	626,484	10/07/1997	5,675,499	Method of Probing a Net of an IC at an Optimal Probe-Point	Granted	P0211
United States	08/13/1996	08/696,346	09/30/1997	5,673,275	Accelerated Mode Tester Timing	Granted	P0220
United States	08/30/1996	705,795	04/06/1999	5,892,949	ATE Test Programming Architecture	Granted	P0233
United States	09/11/1996	110,054	04/26/1998	5,145,003	Driver Circuits for IC Tester	Granted	P0243
United States	10/21/1996	08/734,746	05/05/1998	5,747,818	Thermoelectric Cooling Gas-Assisted FIB System	Granted	P0245
United States	10/22/1996	08/734,994	06/29/1999	5,918,198	Generating Pulses in Analog Channel of ATE Tester	Granted	P0252

PATENT

ATTACHMENT A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDESCENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	11/08/1996	08/745,885	09/28/1999	5,959,458	Method and Apparatus for Measuring Electrical Waveforms using Atomic Force Microscopy	Granted	P0253
United States	11/25/1996	08/756,296	06/20/2000	6,078,845	Apparatus for Carrying Semiconductor Devices	Granted	P0257
United States	12/09/1996	08/762,395	05/05/1998	5,748,124	Analog Channel for Mixed Signal VLSI Tester	Granted	P0222
United States	12/09/1996	08/762,611	05/09/2000	6,061,815	Programming Utility Register to Generate Addresses in Algorithmic Pattern Generator	Granted	P0247
United States	12/19/1996	08/770,621	05/18/1999	5,905,266	Charged Particle Beam System with Optical Microscope	Granted	P0248
United States	12/20/1996	08/771,804	11/24/1998	5,840,630	FIB Etching Enhanced with 1,2 Di-Iodo-Ethane	Granted	P0244
United States	02/18/1997	08/801,687	03/16/1999	5,883,905	Pattern Generator with Extended Register Programming	Granted	P0266
United States	03/03/1997	08/811,104	10/13/1998	5,821,549	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246
United States	03/15/1997	08/818,345	05/18/1999	5,905,577	Dual-Laser Voltage Probing of ICs	Granted	P0261
United States	04/22/1997	08/841,413	07/06/1999	5,920,073	Optical System with an Axially Moveable Apertured Plate	Granted	P0262
United States	05/14/1997	849,290	12/21/1999	6,006,346	Method and Equipment for Automatically Testing Electronic Components	Granted	P0221
United States	05/20/1997	08/858,992	01/11/2000	6,014,764	Providing Test Vectors with Pattern Chaining Definition	Granted	P0254
United States	09/30/1997	08/930,501	11/30/1999	5,996,099	Method and Apparatus for Automatically Testing Electronic Components in Parallel Utilizing Different Timing Signals for each Electronic Component	Granted	P0236
United States	09/30/1997	09/930,492	04/11/2000	6,049,900	Automatic Parallel Electronic Component Testing Method and Equipment	Granted	P0237
United States	09/30/1997	08/930,490	08/31/1999	5,944,846	Method and Apparatus for Selectively Testing Identical Pins of a Plurality of Electronic Components	Granted	P0238
United States	10/14/1997	08/949,747	06/27/2000	6,081,484	Measuring Signals in a Tester System	Granted	P0274
United States	11/24/1997	08/977,649	10/03/2000	6,128,754	Automatic Circuit Tester Having a Waveform Acquisition Mode of Operation	Granted	P0271
United States	05/20/1998	09/082,455	02/29/2000	6,031,229	Automatic Sequencing of FIB Operations	Granted	P0269
United States	09/30/1998	09/163,710	05/01/2001	6,225,626	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246

PATENT

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ATTACHMENT A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDESCENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Granted Date	Patent No.	Title	Status	Docket
United States	04/22/1999	09/284,939	07/17/2001	6,263,464	Device for Controlling Conformity of Consumption of an Electronic Component in a Testing Machine	Granted	P0263
United States	07/09/1999	09/350,611	02/17/2004	6,694,432	Securing Data in a Machine for Testing Electronic Components	Granted	P0291
United States	10/01/1999	09/410,569	---	---	Test Method and Apparatus for Source Synchronous Signals	Inactive	P0309
United States	10/17/1999	09/419,317	12/09/2003	6,661,836	Measuring Jitter of High-Speed Data Channels	Granted	P0299
United States	10/19/1999	09/421,784	12/30/2003	6,671,845	Packet-Based Device Test System	Granted	P0306
United States	10/25/1999	367,376	01/30/2001	6,181,117	Power Supply Circuit of an Electronic Component in a Test Machine	Granted	P0264
United States	11/16/1999	09/440,985	06/25/2002	6,410,924	Energy Filtered Focused Ion Beam Column	Granted	P0281
United States	11/30/1999	09/452,058	09/04/2001	6,285,963	Measuring Signals in a Tester System	Granted	P0274
United States	01/13/2000	09/483,463	06/26/2001	6,252,222	Differential Pulsed Laser Beam Probing of Integrated Circuits	Granted	P0312
United States	02/08/2000	09/500,757	12/17/2002	6,496,261	Double-Pulsed Optical Interferometer for Waveform Probing of Integrated Circuits	Granted	P0316
United States	02/22/2000	09/510,101	04/22/2003	6,553,522	Valuation of Tester Accuracy	Granted	P0303
United States	02/28/2000	09/514,708	12/10/2002	6,492,797	Socket Calibration Method and Apparatus	Granted	P0302
United States	03/15/2000	09/536,979	10/08/2002	6,462,814	Beam Delivery and Imaging for Optical Probing of a Device Operating under Electrical Test	Granted	P0267
United States	03/15/2000	09/526,407	12/17/2002	6,496,953	Calibration Method and Apparatus for Correcting Pulse Width Timing Errors in Integrated Circuit Testing	Granted	P0307
United States	07/28/2000	09/628,116	---	---	Superconducting Single Photon Detector	Pending	P0332
United States	08/22/2000	09/643,576	12/31/2002	6,501,706	Time-To-Digital Converter	Granted	P0296
United States	08/25/2000	09/648,716	09/16/2003	6,622,107	Edge Placement and Jitter Measurement for Electronic Elements	Granted	P0297
United States	09/28/2000	09/675,090	12/31/2002	6,501,288	On-Chip Optically Triggered Latch for IC Time Measurements	Granted	P0324
United States	09/28/2000	09/676,292	---	---	Method and Apparatus for Remotely Testing Semiconductor	Pending	P0340
United States	09/29/2000	09/675,981	10/07/2003	6,630,667	Compact, High Collection Efficiency Scintillator for Secondary Electron Detection	Granted	P0322
United States	09/29/2000	09/676,144	07/16/2002	6,420,888	Test Interface Module	Granted	P0339
United States	10/02/2000	09/679,042	---	---	Method and Apparatus for High Speed IC Test Interface	Pending	P0337

PATENT

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U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDESCENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Doc#
United States	10/24/2000	09/696,102	06/08/2004	6,748,564	Scan Stream Sequencing for Testing Integrated Circuits	Granted	P0321
United States	12/21/2000	09/746,618	---	---	Optical Coupling for Testing Integrated Circuits	Pending	P0329
United States	02/10/2001	09/781,488	02/11/2003	6,518,571	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246
United States	05/31/2001	09/871,541	02/04/2003	6,514,866	Chemical Enhanced Focused Ion Beam Micro-Machining of Copper	Granted	P0345
United States	08/07/2001	09/924,736	01/06/2004	6,672,947	Method for Global Die Thinning and Polishing of Flip-Chip Packaged Integrated Circuits	Granted	P0338
United States	10/18/2001	10/004,018	05/18/2004	6,737,853	Photoconductive-Sampling Voltage Measurement	Granted	P0272
United States	01/23/2002	10/056,287	---	---	Circuit and Method for Distributing Events in an Event Stream	Pending	P0363
United States	01/24/2002	10/057,134	---	---	Comparator Circuit for Differential Swing Comparison and Common-Mode Voltage Comparison	Pending	P0364
United States	01/30/2002	10/066,123	---	---	PICA System Timing Measurement & Calibration	Pending	P0372
United States	02/19/2002	10/079,780	---	---	PICA System Detector Calibration	Pending	P0373
United States	03/18/2002	10/101,564	---	---	Test System Formatters	Pending	P0348
United States	03/19/2002	10/102,526	---	---	Test System Algorithmic Program Generators	Pending	P0350
United States	03/25/2002	10/166,280	---	---	Method and Apparatus for Socket Calibration of Integrated Circuit Testers	Pending	P0352
United States	04/24/2002	10/132,051	02/18/2003	6,522,162	Test System Having Interface Module	Granted	P0339
United States	04/30/2002	10/136,710	---	---	Open-Loop for Waveform Acquisition	Pending	P0355
United States	05/30/2002	10/159,527	---	---	Sub-Resolution Alignment of Images	Pending	P0356
United States	05/30/2002	10/161,272	---	---	Method and Apparatus for Determining Thickness of a Semiconductor Substrate at the Floor	Pending	P0365
United States	05/30/2002	10/160,606	---	---	Method and Apparatus for Forming a Trench Through a Semiconductor Substrate	Pending	P0369
United States	07/16/2002	10/197,134	06/01/2004	6,744,267	Test System and Methodology	Granted	P0370
United States	11/06/2002	10/288,896	---	---	Precise, In-situ Endpoint Detection for Charged Particle Beam	Pending	P0311
United States	02/18/2003	10/371,353	---	---	Signal Paths Providing Multiple Test Configurations	Pending	P0374

PATENT

ATTACHMENT A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDESCENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	03/04/2003	10/382,343	---	---	Method and Apparatus for Accessing Internal Nodes of an Integrated Circuit Using IC Package Substrate	Pending	P0318
United States	04/21/2003	10/420,675	---	---	Method for Surface Preparation to Enable Uniform Etching of Polycrystalline Materials	Pending	P0382
United States	04/23/2003	10/421,059	---	---	Method for Backside Die Thinning and Polishing of Packaged Integrated Circuits	Pending	P0338
United States	10/03/2003	10/678,438	---	---	FIB Milling of Copper over Organic Dielectrics	Pending	P0395
United States	12/08/2003	10/466,366	---	---	Power Supply Device for a Component Testing Installation	Pending	P0353

PATENT ASSIGNMENT

WHEREAS, NPTest, LLC, a limited liability company organized and existing under the laws of the State of Delaware, and having its principal place of business at 150 Baytech Drive, San Jose, California 95134, United States of America (the "Assignor"), is the owner of all right, title, and interest in and to the United States and foreign patents and patent applications (the "Patent Rights") listed in Annex A and Annex B hereto; and

WHEREAS, Credence Systems Corporation, a corporation organized and existing under the laws of the State of Delaware, and having its principal place of business at 1421 California Circle, Milpitas, California 95035, United States of America (the "Assignee"), is desirous of acquiring the entire right, title, and interest in and to said Patent Rights;

WHEREAS, Assignor desires to assign and Assignee desires to receive all of Assignor's right, title and interest in and to the Patent Rights;

NOW THEREFORE, for the sum of \$1.00 and other good and valuable consideration to it in hand paid, the receipt and sufficiency of which are hereby acknowledged, Assignor has sold, assigned, and set over and by these presents does hereby sell, assign and transfer to the said Assignee, and said Assignee's legal representatives, successors and assigns, any and all of the entire right, title and interest in and to said Patent Rights, any applications, provisionals, non-provisionals, continuations, continuations-in-part, continuing prosecutions, divisionals, renewals, or substitutes thereof, all international, foreign and regional applications corresponding thereto, all convention rights corresponding thereto, all priority rights and claims corresponding thereto, and the Letters Patent, both foreign and domestic, that may or shall issue thereon, or any reissues or reexaminations thereof, to be obtained for the Patent Rights;

UPON SAID CONSIDERATION, the Assignor hereby covenants and agrees with the said Assignee that it will not execute any writing or do any act whatsoever conflicting with these presents, and that it will, at any time upon request, without further or additional consideration, but at the expense of the said Assignee, execute such additional assignments and other writings and do such additional acts as said Assignee may deem necessary or desirable to perfect the Assignee's enjoyment of this grant, and render all necessary assistance in making application for and obtaining original, provisionals, non-provisionals, continuations, continuations-in-part, continuing prosecutions, divisionals, renewals, reissued, reexamined or extended Letters Patent of the United States, or of any and all foreign countries, on said Patent Rights, and in enforcing any rights or choses in action accruing as a result of such applications or patents, by giving testimony in any proceedings or transactions involving such applications or patents, and by executing preliminary statements and other affidavits, it being understood that the foregoing covenant and agreement shall bind, and inure to the benefit of, the assigns and legal representatives of both parties.

IN WITNESS WHEREOF, the Assignor has executed this Assignment and caused the same to be duly delivered on its behalf on the day and year first set forth below.

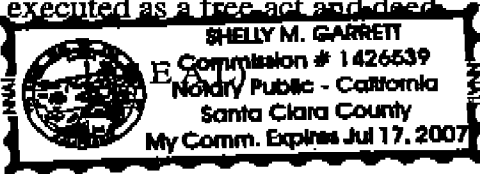
NPTEST, LLC

Date July 12, 2004

By: Julie Weise
Name: Leslie Weise
Title: General Counsel and Secretary

STATE OF CALIFORNIA)
) ss.
COUNTY OF SANTA CLARA)

On this 12 day of July, 2004, before me a Notary Public, personally appeared Leslie Weise, the above-mentioned representative of the Assignor, NPTest, LLC, who executed the foregoing Assignment, and represented and acknowledged that he/she had the requisite corporate authority to execute this Assignment and the same was executed as a free act and deed.



Shelly M. Garrett
Notary Public

My commission expires: July 17, 2007

IN WITNESS WHEREOF, Assignee confirms the acceptance of the assignment of the Patent Rights from the Assignor.

CREDENCE SYSTEMS CORPORATION

Date 7/13/04

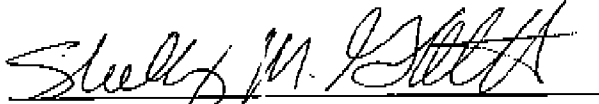
By: [Signature]
Name: Byron Milstead
Title: Vice President and General Counsel

STATE OF CALIFORNIA)
) ss.
COUNTY OF SANTA CLARA)

On this 13 day of July, 2004, before me a Notary Public, personally appeared Byron Milstead, the above-mentioned representative of the Assignee, Credence Systems Corporation, who executed the foregoing Patent Assignment, and represented

and acknowledged that he/she had the requisite corporate authority to execute and accept this Patent Assignment and the same was executed as a free act and deed.

(S E A L)


Notary Public

My commission expires: July 17, 2007



ANNEX A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDECE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	03/07/1983	472,427	06/10/1986	4,594,544	Participate Register for Parallel Loading Pin-Oriented Registers In Test Equipment	Inactive	P0081
REDACTED							
United States	05/17/1984	611,266	03/17/1987	4,651,038	Gate Having Temperatures-Stabilized Delay	Granted	P0117
United States	05/17/1984	611,454	11/18/1986	4,623,802	Multiple-Stage Gate Network Having Independent Reference Voltage Sources	Inactive	P0118
United States	07/18/1984	631,958	06/16/1987	4,673,917	Method and Apparatus for Minimizing Digital-To-Analog Converter Correction Trims	Granted	P0120
United States	08/16/1985	766,905	09/05/1989	4,864,228	Electron Beam Test Probe for Integrated Circuit Testing	Granted	P0150
United States	11/15/1985	798,592	11/10/1987	4,706,019	Electron Beam Test Probe System for Analyzing Integrated Circuits	Granted	P0132
United States	02/10/1986	828,157	01/26/1988	4,721,909	Apparatus for Pulsing Electron Beams	Granted	P0133
United States	11/19/1986	932,762	01/03/1989	4,795,984	Multi-Marker, Multi-Destination Timing Signal Generator	Granted	P0125
REDACTED							
United States	05/17/1988	196,776	03/27/1990	4,912,405	Magnetic Lens and Electron Beam Deflection System	Granted	P0135
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United States	12/12/1988	284,775	03/20/1990	4,910,698	Sine Wave Generator Using A Cordic Algorithm	Granted	P0128
United States	07/13/1990	553,202	02/25/1992	5,091,693	Dual-Sided Test Head Having Floating Contact Surfaces	Granted	P0180
United States	09/05/1990	577,986	05/18/1993	5,212,443	Event Sequencer for Automatic Test Equipment	Granted	P0148
United States	09/05/1990	577,987	07/06/1993	5,225,772	Automatic Test Equipment System Using Pin Slice Architecture	Granted	P0168
United States	01/14/1991	640,636	08/18/1992	5,140,164	IC Modification with Focused ION Beam	Inactive	P0189
United States	02/13/1991	07/655,255	06/30/1992	5,127,064	High Resolution Image Compression Methods and Apparatus	Granted	P0164
United States	06/04/1991	07/710,768	05/11/1993	5,210,487	Double-Gated Integrating Scheme for Electron Beam Tester	Granted	P0191
United States	07/12/1991	729,510	08/10/1993	5,235,273	Apparatus for Settling Pin Driver/Sensor Reference Voltage Level	Granted	P0194

ANNEX A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDEENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	07/17/1991	732,351	06/16/1992	5,122,988	Data Stream Smoothing using a FIFO Memory	Granted	P0172
United States	07/25/1991	737,553	09/01/1992	5,144,225	Methods and Apparatus for Acquiring Data from Intermittently Failing Circuits	Granted	P0173
United States	12/30/1991	816,639	02/21/1995	5,392,222	Locating a Field of View in which Selected IC Conductors are Unobscured	Granted	P0184
United States	04/30/1992	876,566	12/12/1995	5,475,624	Test Generation by Environment Emulation	Granted	P0192
United States	08/12/1992	07/928,919	12/14/1993	5,270,643	Pulsed Laser Photoemission Electron-Beam Probe	Granted	P0188
United States	11/23/1992	07/980,371	10/18/1994	5,357,116	Focused ION Beam Processing with Charge Control	Granted	P0204
United States	03/15/1993	031,547	02/18/1997	5,604,819	Determining Offset between Images of an IC	Granted	P0202
United States	03/24/1993	037,507	02/15/1994	5,287,022	Method and Circuit for Controlling Voltage Reflections on Transmissions Lines	Granted	P0193
United States	05/13/1993	62,362	12/19/1995	5,477,139	Event Sequencer for Automatic Test Equipment	Granted	P0148
United States	08/03/1993	100,975	07/04/1995	5,430,400	Driver Circuits for IC Tester	Granted	P0209
United States	09/02/1993	08/115,997	03/28/1995	5,401,972	Layout Overlay for FIB Operations	Granted	P0210
United States	10/12/1993	08/134,330	01/02/1996	5,481,550	Apparatus For Maintaining Stimulation To A Device Under Test After A Test Stops	Granted	P0203
United States	04/15/1994	228,027	06/25/1996	5,530,372	Method of Probing a Net of an IC at an Optimal Probe-Point	Granted	P0211
United States	06/28/1994	08/267,870	10/24/1995	5,461,310	Automatic Test Equipment System Using Pin Slice Architecture	Granted	P0168
United States	06/30/1994	268,790	04/01/1997	5,616,921	Self-Masking FIB Milling	Granted	P0207
United States	05/04/1995	08/434,548	12/23/1997	5,700,526	Insulator Deposition Using Focused Ion Beam	Granted	P0234
United States	06/08/1995	08/488,650	06/10/1997	5,638,005	Predictive Waveform Acquisition	Granted	P0216
United States	07/17/1995	08/503,023	03/24/1998	5,731,984	Vector-Based Waveform Acquisition and Display	Granted	P0239
United States	08/01/1995	08/510,397	07/08/1997	5,646,521	Analog Channel for Mixed Signal VLSI Tester	Granted	P0222
United States	08/01/1995	08/510,395	08/05/1997	5,654,657	Accurate Alignment of Clocks in Mixed-Signal Tester	Granted	P0228
REDACTED							
United States	12/15/1995	08/573,071	06/15/1999	5,913,022	Loading Hardware Pattern Memory in Automatic Test Equipment for Testing Circuits	Granted	P0231
United States	04/02/1996	626,484	10/07/1997	5,675,499	Method of Probing a Net of an IC at an Optimal Probe-Point	Granted	P0211

ANNEX A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDESCENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	08/13/1996	08/696,346	09/30/1997	5,673,275	Accelerated Mode Tester Timing	Granted	P0220
United States	08/30/1996	705,795	04/06/1999	5,892,949	ATE Test Programming Architecture	Granted	P0233
United States	09/11/1996	710,032	04/28/1998	5,745,003	Driver Circuits for IC Tester	Granted	P0243
United States	10/21/1996	08/734,746	05/05/1998	5,747,818	Thermoelectric Cooling Gas-Assisted FIB System	Granted	P0245
United States	10/22/1996	08/734,994	06/29/1999	5,918,198	Generating Pulses in Analog Channel of ATE Tester	Granted	P0252
United States	11/08/1996	08/745,885	09/28/1999	5,959,458	Method and Apparatus for Measuring Electrical Waveforms using Atomic Force Microscopy	Granted	P0253
United States	11/25/1996	08/756,296	06/20/2000	6,078,845	Apparatus for Carrying Semiconductor Devices	Granted	P0257
United States	12/09/1996	08/762,395	05/05/1998	5,748,124	Analog Channel for Mixed Signal VLSI Tester	Granted	P0222
United States	12/09/1996	08/762,611	05/09/2000	6,061,815	Programming Utility Register to Generate Addresses in Algorithmic Pattern Generator	Granted	P0247
United States	12/19/1996	08/770,621	05/18/1999	5,905,266	Charged Particle Beam System with Optical Microscope	Granted	P0248
United States	12/20/1996	08/771,804	11/24/1998	5,840,630	FIB Etching Enhanced with 1,2 Di-Iodo-Ethane	Granted	P0244
REDACTED							
United States	02/18/1997	08/801,687	03/16/1999	5,883,905	Pattern Generator with Extended Register Programming	Granted	P0266
United States	03/03/1997	08/811,104	10/13/1998	5,821,549	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246
United States	03/15/1997	08/818,345	05/18/1999	5,905,577	Dual-Laser Voltage Probing of ICs	Granted	P0261
United States	04/22/1997	08/841,413	07/06/1999	5,920,073	Optical System with an Axially Moveable Apertured Plate	Granted	P0262
United States	05/14/1997	849,290	12/21/1999	6,006,346	Method and Equipment for Automatically Testing Electronic Components	Granted	P0221
United States	05/20/1997	08/858,992	01/11/2000	6,014,764	Providing Test Vectors with Pattern Chaining Definition	Granted	P0254
United States	06/30/1997	08/930,501	11/20/1999	5,999,000	Method and Apparatus for Automatically Testing Electronic Components in Parallel Utilizing Different Timing Signals for each Electronic Component	Granted	P0230
United States	09/30/1997	09/930,492	04/11/2000	6,049,900	Automatic Parallel Electronic Component Testing Method and Equipment	Granted	P0237

ANNEX A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDESCENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	09/30/1997	08/930,490	08/31/1999	5,944,846	Method and Apparatus for Selectively Testing Identical Pins of a Plurality of Electronic Components	Granted	P0238
United States	10/14/1997	08/949,747	06/27/2000	6,081,484	Measuring Signals in a Tester System	Granted	P0274
United States	11/24/1997	08/977,649	10/03/2000	6,128,754	Automatic Circuit Tester Having a Waveform Acquisition Mode of Operation	Granted	P0271
United States	05/20/1998	09/082,455	02/29/2000	6,031,229	Automatic Sequencing of FIB Operations	Granted	P0269
United States	09/30/1998	09/163,710	05/01/2001	6,225,626	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246
United States	04/22/1999	09/284,939	07/17/2001	6,263,464	Device for Controlling Conformity of Consumption of an Electronic Component in a Testing Machine	Granted	P0263
United States	07/09/1999	09/350,611	02/17/2004	6,694,432	Securing Data in a Machine for Testing Electronic Components	Granted	P0291
United States	10/01/1999	09/410,569	---	---	Test Method and Apparatus for Source Synchronous Signals	Inactive	P0309
United States	10/17/1999	09/419,317	12/09/2003	6,661,836	Measuring Jitter of High-Speed Data Channels	Granted	P0299
United States	10/19/1999	09/421,784	12/30/2003	6,671,845	Packet-Based Device Test System	Granted	P0306
United States	10/25/1999	367,376	01/30/2001	6,181,117	Power Supply Circuit of an Electronic Component in a Test Machine	Granted	P0264
United States	11/16/1999	09/440,985	06/25/2002	6,410,924	Energy Filtered Focused Ion Beam Column	Granted	P0281
United States	11/30/1999	09/452,058	09/04/2001	6,285,963	Measuring Signals in a Tester System	Granted	P0274
United States	01/13/2000	09/483,463	06/26/2001	6,252,222	Differential Pulsed Laser Beam Probing of Integrated Circuits	Granted	P0312
United States	02/08/2000	09/500,757	12/17/2002	6,496,261	Double-Pulsed Optical Interferometer for Waveform Probing of Integrated Circuits	Granted	P0316
United States	02/22/2000	09/510,101	04/22/2003	6,553,522	Valuation of Tester Accuracy	Granted	P0303
United States	02/28/2000	09/514,708	12/10/2002	6,492,797	Socket Calibration Method and Apparatus	Granted	P0302
United States	03/15/2000	09/526,979	10/08/2002	6,462,814	Beam Delivery and Imaging for Optical Probing of a Device Operating under Electrical Test	Granted	P0267
United States	03/15/2000	09/526,407	12/17/2002	6,496,953	Calibration Method and Apparatus for Correcting Pulse Width Timing Errors in Integrated Circuit Testing	Granted	P0307
United States	07/28/2000	09/628,116	---	---	Superconducting Single Photon Detector	Pending	P0332
United States	08/22/2000	09/643,576	12/31/2002	6,501,706	Time-To-Digital Converter	Granted	P0296
United States	08/25/2000	09/648,716	09/16/2003	6,622,107	Edge Placement and Jitter Measurement for Electronic Elements	Granted	P0297

PATENT

REEL: 015242 FRAME: 0587

ANNEX A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDESCENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	09/28/2000	09/675,090	12/31/2002	6,501,288	On-Chip Optically Triggered Latch for IC Time Measurements	Granted	P0324
United States	09/28/2000	09/676,292	---	---	Method and Apparatus for Remotely Testing Semiconductor	Pending	P0340
United States	09/29/2000	09/675,981	10/07/2003	6,630,667	Compact, High Collection Efficiency Scintillator for Secondary Electron Detection	Granted	P0322
United States	09/29/2000	09/676,144	07/16/2002	6,420,888	Test Interface Module	Granted	P0339
United States	10/02/2000	09/679,042	---	---	Method and Apparatus for High Speed IC Test Interface	Pending	P0337
United States	10/24/2000	09/696,102	06/08/2004	6,748,564	Scan Stream Sequencing for Testing Integrated Circuits	Granted	P0321
United States	12/21/2000	09/746,618	---	---	Optical Coupling for Testing Integrated Circuits	Pending	P0329
United States	02/10/2001	09/781,488	02/11/2003	6,518,571	Through the Substrate Investigation of Flip-Chip ICs	Granted	P0246
REDACTED							
United States	05/31/2001	09/871,541	02/04/2003	6,514,866	Chemical Enhanced Focused Ion Beam Micro-Machining of Copper	Granted	P0345
United States	08/07/2001	09/924,736	01/06/2004	6,672,947	Method for Global Die Thinning and Polishing of Flip-Chip Packaged Integrated Circuits	Granted	P0338
United States	10/18/2001	10/004,018	05/18/2004	6,737,853	Photoconductive-Sampling Voltage Measurement	Granted	P0272
United States	01/23/2002	10/056,287	---	---	Circuit and Method for Distributing Events in an Event Stream	Pending	P0363
United States	01/24/2002	10/057,134	---	---	Comparator Circuit for Differential Swing Comparison and Common-Mode Voltage Comparison	Pending	P0364
United States	01/30/2002	10/066,123	---	---	PiCA System Timing Measurement & Calibration	Pending	P0372
PATENT							
United States	02/19/2002	10/079,780	---	---	PiCA System Detector Calibration	Pending	P0373
United States	03/18/2002	10/101,564	---	---	Test System Formatters	Pending	P0348

ANNEX A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDEENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	03/19/2002	10/102,526	---	---	Test System Algorithmic Program Generators	Pending	P0350
United States	03/25/2002	10/106,280	---	---	Method and Apparatus for Socket Calibration of Integrated Circuit Testers	Pending	P0352
United States	04/24/2002	10/132,051	02/18/2003	6,522,162	Test System Having Interface Module	Granted	P0339
United States	04/30/2002	10/136,710	---	---	Open-Loop for Waveform Acquisition	Pending	P0355
United States	05/30/2002	10/159,527	---	---	Sub-Resolution Alignment of Images	Pending	P0356
United States	05/30/2002	10/161,272	---	---	Method and Apparatus for Determining Thickness of a Semiconductor Substrate at the Floor	Pending	P0365
United States	05/30/2002	10/160,606	---	---	Method and Apparatus for Forming a Trench Through a Semiconductor Substrate	Pending	P0369
United States	07/16/2002	10/197,134	06/01/2004	6,744,267	Test System and Methodology	Granted	P0370

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PATENT

REEL: 015242 FRAME: 0589

ANNEX A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDEENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	11/06/2002	10/288,896	---	---	Precise, In-situ Endpoint Detection for Charged Particle Beam	Pending	P0311
REDACTED							
United States	02/18/2003	10/371,353	---	---	Signal Paths Providing Multiple Test Configurations	Pending	P0374
REDACTED							
United States	03/04/2003	10/382,343	---	---	Method and Apparatus for Accessing Internal Nodes of an Integrated Circuit Using IC Package Substrate	Pending	P0318
REDACTED							
United States	04/21/2003	10/420,675	---	---	Method for Surface Preparation to Enable Uniform Etching of Polycrystalline Materials	Pending	P0382
United States	04/23/2003	10/421,059	---	---	Method for Backside Die Thinning and Polishing of Packaged Integrated Circuits	Pending	P0338
REDACTED							

PATENT

ANNEX A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDEENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
United States	10/03/2003	10/678,438	---	---	FIB Milling of Copper over Organic Dielectrics	Pending	P0395
REDACTED							
United States	12/08/2003	10/466,366	---	---	Power Supply Device for a Component Testing Installation	Pending	P0353
REDACTED							

PATENT

ANNEX A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDESCENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
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REDACTED

PATENT

ANNEX A
U.S. PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDEENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
REDACTED							

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
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REDACTED

PATENT

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
REDACTED							

PATENT

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDEENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
REDACTED							

PATENT

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CRENDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
REDACTED							

PATENT

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDEENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
REDACTED							

PATENT

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDECE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
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PATENT

REEL: 015242 FRAME: 0599

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
REDACTED							

PATENT

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDESCENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
REDACTED							
PATENT							

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDECE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
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REDACTED

PATENT

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDESCENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
REDACTED							

PATENT

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDEENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
REDACTED							

PATENT

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDESCENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
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REDACTED

PATENT

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
REDACTED							

PATENT

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
REDACTED							
PATENT							

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDESCENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
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REDACTED

PATENT

ANNEX B
FOREIGN PATENT ASSIGNMENT FROM NPTEST, LLC TO CREDEENCE SYSTEMS CORPORATION

Country	Application Date	Application No.	Grant Date	Patent No.	Title	Status	Docket
REDACTED							